

11A, 500V N-CHANNEL POWER MOSFET

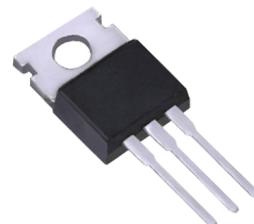
■ DESCRIPTION

The **UTC 11N50** is an N-channel enhancement mode power MOSFET. It uses UTC advanced planar stripe, DMOS technology to provide customers perfect switching performance, minimal on-state resistance. It also can withstand high energy pulse in the avalanche and commutation mode.

The **UTC 11N50** is universally applied in electronic lamp ballasts based on half bridge topology, high efficiency switched mode power supplies, active power factor correction, etc.

■ FEATURES

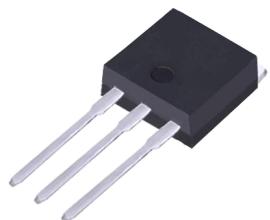
- * $R_{DS(ON)}=0.55\Omega$ @ $V_{GS}=10V$
- * Fast Switching
- * With 100% Avalanche Tested



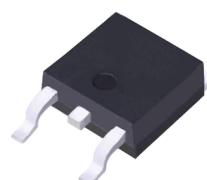
TO-220



TO-220F



TO-262



TO-263



TO-251



TO-252

■ ABSOLUTE MAXIMUM RATINGS ($T_c = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain to Source Voltage		V_{DSS}	500	V
Gate to Source Voltage		V_{GSS}	± 30	V
Continuous Drain Current	$T_c=25^\circ\text{C}$	I_D	11 (Note 2)	A
	$T_c=100^\circ\text{C}$		7 (Note 2)	A
Pulsed Drain Current (Note 3)		I_{DM}	44 (Note 2)	A
Single Pulsed Avalanche Energy (Note 4)		E_{AS}	670	mJ
Peak Diode Recovery dv/dt (Note 5)		dv/dt	4.5	V/ns
Power Dissipation	$T_c=25^\circ\text{C}$	TO-220 TO-220F1 TO-220F TO-262	195	W
			40	
			48	
			195	
	Derate above 25°C	TO-220 TO-220F1 TO-220F	1.56	W/ $^\circ\text{C}$
			0.32	
			0.39	
		TO-262	1.56	
Junction Temperature		T_J	+150	$^\circ\text{C}$
Storage Temperature		T_{STG}	-55 ~ +150	$^\circ\text{C}$

- Note:
1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.
Absolute maximum ratings are stress ratings only and functional device operation is not implied.
 2. Drain current limited by maximum junction temperature
 3. Repetitive Rating : Pulse width limited by maximum junction temperature
 4. $L=10\text{mH}$, $I_{AS}=11\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\Omega$, Starting $T_J=25^\circ\text{C}$
 5. $I_{SD} \leq 11\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J=25^\circ\text{C}$

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient		θ_{JA}	62.5	$^\circ\text{C/W}$
Junction to Case	TO-220 TO-220F1 TO-220F TO-262	θ_{JC}	0.64	$^\circ\text{C/W}$
			3.1	
			2.58	
			0.64	

■ ELECTRICAL CHARACTERISTICS ($T_c=25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	500			V
Breakdown Voltage Temperature Coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	$I_{\text{D}}=250\mu\text{A}$, Referenced to 25°C		0.5		$\text{V}/^\circ\text{C}$
Drain-Source Leakage Current	I_{DSS}	$V_{\text{DS}}=500\text{V}, V_{\text{GS}}=0\text{V}$ $V_{\text{DS}}=500\text{V}, T_J=125^\circ\text{C}$		10		μA
Gate-Source Leakage Current	I_{GSS}	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=\pm 30\text{V}$			± 100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0		4.0	V
Drain-Source On-State Resistance	$R_{\text{DS(ON)}}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=5.5\text{A}$		0.48	0.55	Ω
DYNAMIC PARAMETERS						
Input Capacitance	C_{ISS}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1.0\text{MHz}$		1515	2055	pF
Output Capacitance	C_{OSS}			185	235	pF
Reverse Transfer Capacitance	C_{RSS}			25	30	pF
SWITCHING PARAMETERS						
Total Gate Charge	Q_G	$V_{\text{DS}}=400\text{V}, V_{\text{GS}}=10\text{V}, I_{\text{D}}=11\text{A}$ (Note 1, 2)		43	55	nC
Gate-Source Charge	Q_{GS}			8		nC
Gate-Drain Charge	Q_{GD}			19		nC
Turn-ON Delay Time	$t_{\text{D(ON)}}$	$V_{\text{DD}}=250\text{V}, I_{\text{D}}=11\text{A}, R_{\text{G}}=3\Omega$ (Note 1, 2)		24	57	ns
Turn-ON Rise Time	t_R			70	150	ns
Turn-OFF Delay Time	$t_{\text{D(OFF)}}$			120	250	ns
Turn-OFF Fall Time	t_F			75	160	ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Body-Diode Continuous Current	I_S				11	A
Maximum Body-Diode Pulsed Current	I_{SM}				44	A
Drain-Source Diode Forward Voltage	V_{SD}	$I_S=11\text{A}, V_{\text{GS}}=0\text{V}$			1.4	V
Body Diode Reverse Recovery Time	t_{rr}	$V_{\text{GS}}=0\text{V}, I_S=11\text{A},$		90		ns
Body Diode Reverse Recovery Charge	Q_{RR}	$dI_F/dt=100\text{A}/\mu\text{s}$ (Note 1)		1.5		μC

Note: 1. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$

2. Essentially independent of operating temperature